In re Appln. of TAKEUCHI et al. Application No. Unassigned

ABSTRACT AMENDMENTS

Replace the Abstract with:

In a method of evaluating a piezoelectric field, a non-destructive spectrometry of piezoelectric fields is performed in a semiconductor heterojunction using a technique different from PR spectroscopy. In the method, at first, first and second absorption spectra are measured by irradiating the sample with infrared light to a sample with at first and second angles, respectively. Then, a peak position of an absorption band having incident-angle dependent intensity is specified, based on the first and second absorption spectra. Thus, the piezoelectric field strength is obtained based on an equation of energy level. The equation represents using a relationship between the piezoelectric field and an electron energy level corresponding to the peak position.